On-chip di/dt Detector Circuit for Power Supply Line

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Background

- di/dt is becoming a critical issue
 - L(di/dt) noise of low voltage LSIs
 - EMI noise of high-speed operation LSIs
- Need to measure the di/dt



Conventional Current Meas.

- Probe the voltage difference of the R

 Needs numerical calculation
- Probe the magnetic field by pickup coil
 Phase information is lost



Contents

- Introduction of our di/dt detector circuit
 - Mutual Inductor
 - Amplifier
 - Setup for measurement
- Simulation Waveforms
- Summary

Block Diagram

- L2 picks up the di/dt, induce the voltage
- Amplifier amplifies/output the voltage



Advantage

- On-chip
- di/dt waveform without numerical calculation
- Real time
- Feedback di/dt control is possible

Mutual Inductor



Equivalent Circuit

Extracted by FastHenry



Amplifier/Output buffer



Noise Tolerance

- Common mode noise is eliminated
- Vdd noise is suppressed to 14% (by 86%)



Single or Dual?

- Noise immunity, Sensitivity, Symmetric
- Require two pins, numerical calculation



Linearity of the Amplifier



Sensitivity

• L1=0.499nH, L2=14.5nH, K=0.652, G=1.273



Test Circuit



Whole Test Circuit



di/dt Waveform (repeat)



di/dt Waveform (random)



Current Waveforms



Summary

- An on-chip di/dt detector is proposed.
- It consists of a spiral inductor and an amplifier.
- The accuracy is 1.52x10⁷ A/s by an HSPICE simulation (random case).
- Current waveform can be obtained by integration of the di/dt output, with the accuracy of 0.72mA.

